



• EXAFS theory



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- Local structure of nanoferritic alloy steels



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Reading Assignment: Chapter 7.4



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Reading Assignment: Chapter 7.4

Homework Assignment #05: Chapter 5: 1,3,7,9,10 due Tuesday, November 02, 2021



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- Local structure of nanoferritic alloy steels
- In situ studies of methanol fuel cells

Reading Assignment: Chapter 7.4

Homework Assignment #05: Chapter 5: 1,3,7,9,10 due Tuesday, November 02, 2021 Homework Assignment #06: Chapter 6: 1,6,7,8,9 due Tuesday, November 16, 2021





X-ray absorption needs an available state for the photoelectron to go into

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An atom absorbs an x-ray of energy E, destroying a core electron with energy E_0 and creating a photoelectron with energy $(E - E_0)$. The core hole is eventually filled, and a fluorescence x-ray or Auger electron is ejected from the atom.

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In the EXAFS region, the backscattered photoelectron will interfere with itself

The amplitude and phase of the back-scattered photoelectron at the absorbing atom will vary with energy, causing the oscillations in $\mu(E)$







$$\mu(E) = \mu_0(E) + \Delta \mu(E)$$

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October 28, 2021

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$$\mu(E) = \mu_0(E) + \Delta \mu(E) = \mu_0(E)[1 + \chi(E)]$$





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 ${\cal H}$ is the interaction. In the dipole approximation, ${\cal H}=e^{ikr}\approx 1.$

 $|f\rangle$ is the final state which has a photoelectron, a hole in the core, and no photon. This is altered by the neighboring atom: the photoelectron scatters.







Writing $|f\rangle = |f_0 + \Delta f\rangle$, where Δf gives the change in photoelectron final state due to backscattering from the neighboring atom, we can expand μ to get

 $\mu(E) \sim |\langle i | \mathcal{H} | f \rangle|^2$



$$\mu(E) \sim |\langle i | \mathcal{H} | f \rangle|^2 = \langle i | \mathcal{H} | f_0 + \Delta f \rangle \langle f_0 + \Delta f | \mathcal{H} | i \rangle$$



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where scattering from the neighboring atom gives the amplitude
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 and phase-shift $\delta(k)$ to the photoelectron

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$$\chi(k) \sim \psi_{scatt}(0) = \frac{e^{ikR}}{kR} [2kf(k)e^{i\delta(k)}] \frac{e^{ikR}}{kR} = \frac{2e^{i(2kR+\delta(k))}}{kR^2} f(k)$$

where scattering from the neighboring atom gives the amplitude $f(k)$ and phase-shift $\delta(k)$ to

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Including the complex conjugate,

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$$\chi(k) \sim \frac{2f(k)}{kR^2} \left[e^{i(2kR+\delta(k))} + e^{-i(2kR+\delta(k))} \right]$$

Including the complex conjugate, and simplifying

$$\chi(k) \sim \frac{2f(k)}{kR^2} \left[e^{i(2kR+\delta(k))} + e^{-i(2kR+\delta(k))} \right] = \frac{f(k)}{kR^2} \cos\left[2kR + \delta(k)\right]$$



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$$\chi(k) = rac{f(k)}{kR^2} \sin\left[2kR + \delta(k)
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Z can usually be determined to $\pm 5.$ Fe and O can be distinguished, but Fe and Mn cannot be



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Generally, the calculations (FEFF, etc) include these effects. We'll discuss of few of these in more detail \ldots

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for 3 Å $^{-1}$ < k < 15 Å $^{-1}$, λ < 30 Å

along with the R^{-2} term this makes EXAFS a local atomic probe

for XANES ($k < 3 \text{ Å}^{-1}$), both λ and R^{-2} become large: making XANES not really a local probe





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This, and other experimental and theoretical issues, make EXAFS amplitudes (and therefore N) less precise than EXAFS phases (and therefore R)

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The full EXAFS equation can be used to model and interpret experimental data



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Because we can compute f(k) and $\delta(k)$, and $\lambda(k)$ we can determine Z, R, N, and σ^2 for scattering paths to neighboring atoms by fitting the data.

Sum over paths and multiple scattering



A sum over scattering paths allows multiple-scattering paths: the photoelectron scatters from more than one atom before returning to the absorbing atom:

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Single Scattering Triangle Paths



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For first shell analysis, multiple scattering is hardly ever needed

Carlo Segre (Illinois Tech)

Advantages of nanoferritic alloy (NFA) steels

High density nanofeatures (NFs) and dislocations provide irradiation damage resistance

NFs trap helium in fine bubbles and prevent accumulation of high concentrations

 ${\sf NFs}$ maintain high stable sink densities for vacancy and self-interstitial atom defect annihilation

 ${\sf NFs}$ maintain high creep strength because of dislocation pinning, allowing operation at temperatures above the displacement damage regime

G.R. Odette, M.J. Alinger, and B.D. Wirth, Annu. Rev. Mater. Res. 38, 471-503 (2008).



Fabrication of NFA steels





Atom probe tomography data

distributed throughout the solid

V

Cr

C.A. Williams, P. Unifantowicz, N. Baluc, G.D.W. Smith, and E.A. Marquis, Acta Materialia 61, 2219–2235 (2013).

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Consolidated materials show Ti-O and Y to be primarily co-localized in nanoclusters

Use XAS to understand the local structure of these nanoclusters $% \left({{{\rm{AS}}} \right)$

C.A. Williams, P. Unifantowicz, N. Baluc, G.D.W. Smith, and E.A. Marquis, Acta Materialia 61, 2219–2235 (2013).

Samples studied



Sample name	Composition (wt %)					Processing
	Cr	Ti	Мо	W	$Y_{2}O_{3}$	
MA957	14	1	0.3		0.3	hot extruded @ 1150°C
J12YWT	12	0.4		3	0.25	hot extruded @ $1150^{\circ}C$
as received	14	0.4		3		as received powder
as milled	14	0.4		3	0.25	mechanically alloyed powder
850°C	14	0.4		3	0.25	powder annealed @ 850°C
1000°C	14	0.4		3	0.25	powder annealed @ $1000^{\circ}C$
1150°C	14	0.4		3	0.25	powder annealed @ 1150° C

Samples consolidated from as milled powder by hot isostatic pressing were shown to be identical to annealed powders and are thus not discussed.

Carlo Segre (Illinois Tech)

Yttrium edge data





Edges show complex mixture of phases

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Yttrium edge data





Edges show complex mixture of phases

EXAFS of annealed powders indicate smaller NFs than commercial steels



Titanium edge data



As received, as milled and commercial steels all show a metallic environment; annealed powder edges resemble TiO



Titanium edge data





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Ti in BCC structure





As received data can be fit with a simple BCC Fe model

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Ti in BCC structure







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Ti in BCC structure

Carlo Segre (Illinois Tech)





As received data can be fit with a simple BCC Fe model MA957 $|k^2\chi(R)|\;[\mathring{A}^3]$ J12YWT 2 R [Å] Commercial alloys fit with this model plus a small amount of Ti-O neighbors

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Ti in TiO structure

Annealed powders have a remarkable resemblance to the cubic TiO calculated spectrum





Ti in TiO structure





All can be fit with cubic TiO plus an additional Ti-O path, likely from complex Y-Ti-O oxides

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Commercial steels retain Ti in a metallic BCC lattice for the most part



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Annealed powders all have mixture of TiO-like structure and more complex oxides ($\sim 50\%$ each)



"Evidence for core-shell nanoclusters in oxygen dispersion strengthened steels measured using x-ray absorption spectroscopy," S. Liu, G.R. Odette, and C.U. Segre, J. Nucl. Mater. 445, 50-56 (2014).



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Presence of this metastable cubic TiO suggests significant fraction of Ti on the surface of Y–Ti–O NFs $\,$



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